

ARFTG Cumulative Index: 1989-1996

This is a cumulative index of all papers presented at the semiannual [Automatic RF Techniques Group \(ARFTG\)](#) Conference, from the 33rd Conference in Spring of 1989 through the 48th Conference in Fall of 1996. The listing is alphabetical by author, with a separate listing for each author of each paper.

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